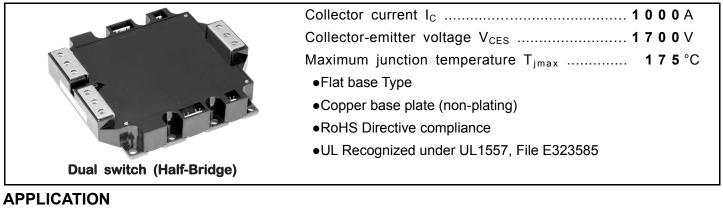
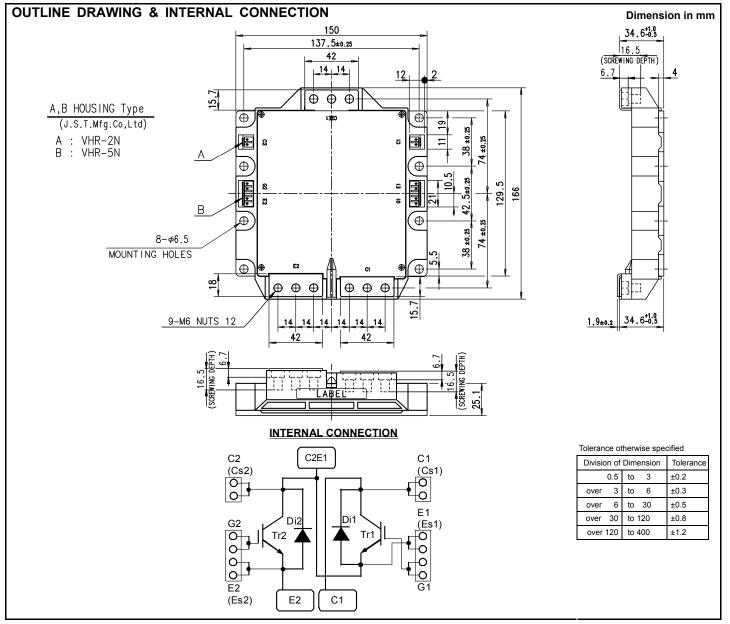


< IGBT MODULES > CM1000DUC-34SA

HIGH POWER SWITCHING USE INSULATED TYPE



Wind power, Photovoltaic (Solar) power, AC Motor Control, Motion/Servo Control, Power supply, etc.



ABSOLUTE MAXIMUM RATINGS (Tj=25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit	
V _{CES}	Collector-emitter voltage	G-E short-circuited	1700	V	
V_{GES}	Gate-emitter voltage	C-E short-circuited	± 20	V	
Ic	Collector current	DC, T _C =125 °C (Note2, 4)	1000	^	
I _{CRM}	Collector current	Pulse, Repetitive (Note3)	2000	A	
P _{tot}	Total power dissipation	T _C =25 °C (Note2, 4)	10000	W	
IE (Note1)		(Note2)	1000	^	
I _{ERM} (Note1)	Emitter current	Pulse, Repetitive (Note3)	2000	A	
V _{isol}	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V	
T _{jmax}	Maximum junction temperature	Instantaneous event (overload)	175	°C	
T _{cmax}	Maximum case temperature	(Note4)	125		
Tjop	Operating junction temperature	Continuous operation (under switching)	-40 ~ +150	°C	
T _{stg}	Storage temperature	-	-40 ~ +125		

ELECTRICAL CHARACTERISTICS (T_j=25 °C, unless otherwise specified)

Symbol	Item	Conditions			Limits		Unit
Symbol	item	Conditions		Min.	Тур.	Max.	Unit
I _{CES}	Collector-emitter cut-off current	V _{CE} =V _{CES} , G-E short-circuited		-	-	1.0	mA
I _{GES}	Gate-emitter leakage current	V_{GE} = V_{GES} , C-E short-circuited		-	-	10	μA
$V_{\text{GE(th)}}$	Gate-emitter threshold voltage	I _C =100 mA, V _{CE} =10 V		5.4	6.0	6.6	V
		I _C =1000 A ^(Note5) ,	T _j =25 °C	-	1.9	2.4	
V_{CEsat}	Collector-emitter saturation voltage	V _{GE} =15 V,	T _j =125 °C	-	2.1	-	V
		Terminal=chip	T _j =150 °C	-	2.15	-	1
Cies	Input capacitance		-	-	260		
C _{oes}	Output capacitance	V _{CE} =10 V, G-E short-circuited		-	-	27	nF
Cres	Reverse transfer capacitance			-	-	5	
Q _G	Gate charge	V _{cc} =1000 V, I _c =1000 A, V _{GE} =15 V		-	4700	-	nC
t _{d(on)}	Turn-on delay time	V_{cc} =1000 V, I _c =1000 A, V _{GE} =±15 V, R _G =2.0 Ω, Inductive load		-	-	900	
tr	Rise time			-	-	350	1
t _{d(off)}	Turn-off delay time			-	-	1250	ns
t _f	Fall time			-	-	400	1
		I _E =1000 A ^(Note5) ,	T _j =25 °C	-	4.0	5.2	
V _{EC} (Note1)	Emitter-collector voltage	G-E short-circuited,	T _j =125 °C	-	2.8	-	V
		Terminal=chip	T _j =150 °C	-	2.6	-	1
t _{rr} ^(Note1)	Reverse recovery time	V _{cc} =1000 V, I _E =1000 A, V _{GE} =±15 V,		-	-	400	ns
Q _{rr} (Note1)	Reverse recovery charge	R_{g} =2.0 Ω , Inductive load		-	270	-	μC
Eon	Turn-on switching energy per pulse	V _{cc} =1000 V, I _c =I _F =1000 A,		-	239	-	
E _{off}	Turn-off switching energy per pulse	V _{GE} =±15 V, R _G =2.0 Ω,		-	269	-	mJ
Err (Note1)	Reverse recovery energy per pulse	T _i =150 °C, Inductive load		-	130	-	mJ
R _{CC'+EE'}	Internal lead resistance	Main terminals-chip, per switch, T _c =25 °C ^(Note4)		-	0.286	-	mΩ
r _g	Internal gate resistance	Per switch		-	0.56	-	Ω

THERMAL RESISTANCE CHARACTERISTICS

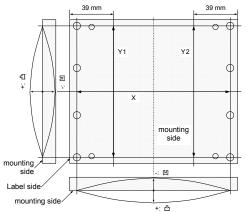
Symbol	Item	Conditions	Limits			Unit
	nem	Conditions	Min.	Тур.	Max.	Unit
R _{th(j-c)Q}	Thermal resistance (Note4)	Junction to case, per IGBT	-	-	15	K/kW
R _{th(j-c)D}		Junction to case, per FWDi	-	-	24	K/kW
R _{th(c-s)}	Contact thermal resistance (Note4)	Case to heat sink, per 1/2 module,		12	-	K/kW
		Thermal grease applied (Note6)	-	12		IVEN

MECHANICAL CHARACTERISTICS

Symbol	Item	Conditions		Limits			Unit
				Min.	Тур.	Max.	Unit
Mt	- Mounting torque	Main terminals	M 6 screw	3.5	4.0	4.5	N∙m
Ms		Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N∙m
ds	Creepage distance	Terminal to terminal		24	-	-	mm
		Terminal to base plate		33	-	-	
d _a Clearance	Clearance	Terminal to terminal		14	-	-	mm
	Clearance	Terminal to base plate		33	-	-	mm
m	Weight	-		-	1450	-	g
ec	Flatness of base plate	On the centerline X, Y1, Y2 (*	Note7)	-50	-	+100	μm

Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free wheeling diode (FWDi).

- 2. Junction temperature (T_j) should not increase beyond T_{jmax} rating.
- 3. Pulse width and repetition rate should be such that the device junction temperature (T_j) dose not exceed T_{jmax} rating.
- 4. Case temperature (T_c) and heat sink temperature (T_s) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.
- The heat sink thermal resistance should measure just under the chips.
- 5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.
- 6. Typical value is measured by using thermally conductive grease of λ =0.9 W/(m·K).
- 7. Base plate (mounting side) flatness measurement points (X, Y1 and Y2) are as follows of the following figure.



8. The company name and product names herein are the trademarks and registered trademarks of the respective companies.

RECOMMENDED OPERATING CONDITIONS

Symbol	Item	Conditions	Limits			Unit
	item	Conditions	Min.	Тур.	Max.	Unit
Vcc	(DC) Supply voltage	Applied across C1-E2	-	1000	1200	V
V _{GEon}	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2	13.5	15.0	16.5	V
R _G	External gate resistance	Per switch	2.0	-	6.0	Ω

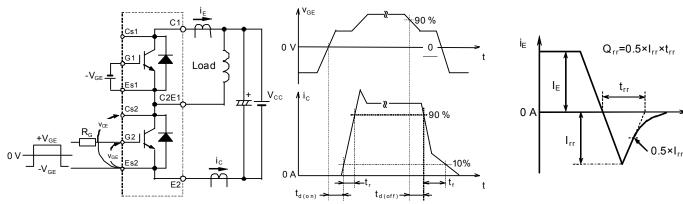
CHIP LOCATION (Top view)

111.1 99.1 ∞ თ 38. 50. 0 Ф \bigcirc \bigcirc \bigcirc \bigcirc 0 \oplus \oplus CZEJ 119.3-Tr2-Di2-Di1-Tr1 (38) 106.2 Tr2-Di2 Di1—Tr1 5 22 U-93.2--Tr2 – Di2-Di1—Tr1 \oplus \oplus 77.8 Tr2-Di2-Di1-Tr1 0 R ũ 5 5) 8 (166) (129. 64.7 -Tr2 - Di2-Di1—Tr1 (42. 8 8 5 -Tr2 - Di2-Di1—Tr1 51.7 \oplus \oplus 36.3-Di1—Tr1 Tr2—Di2 (38) 23.2-Di1—Tr1 Tr2—Di2--Tr2 — Di2-Di1—Tr1 10.2- $\overline{\oplus}$ ٢ ٢ \oplus C1 0 0 (\cdot) (\cdot) \oplus (\cdot) () (\cdot) (137.5)(150) LABEL SIDE

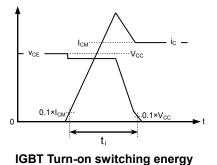
Tr1/Tr2: IGBT, Di1/Di2: FWDi

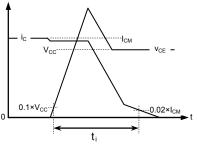
Dimension in mm, tolerance: ±1 mm

TEST CIRCUIT AND WAVEFORMS

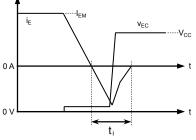


Switching characteristics test circuit and waveforms







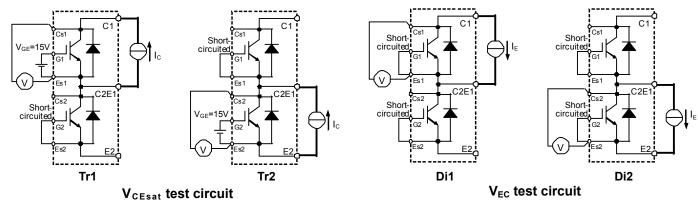


IGBT Turn-off switching energy

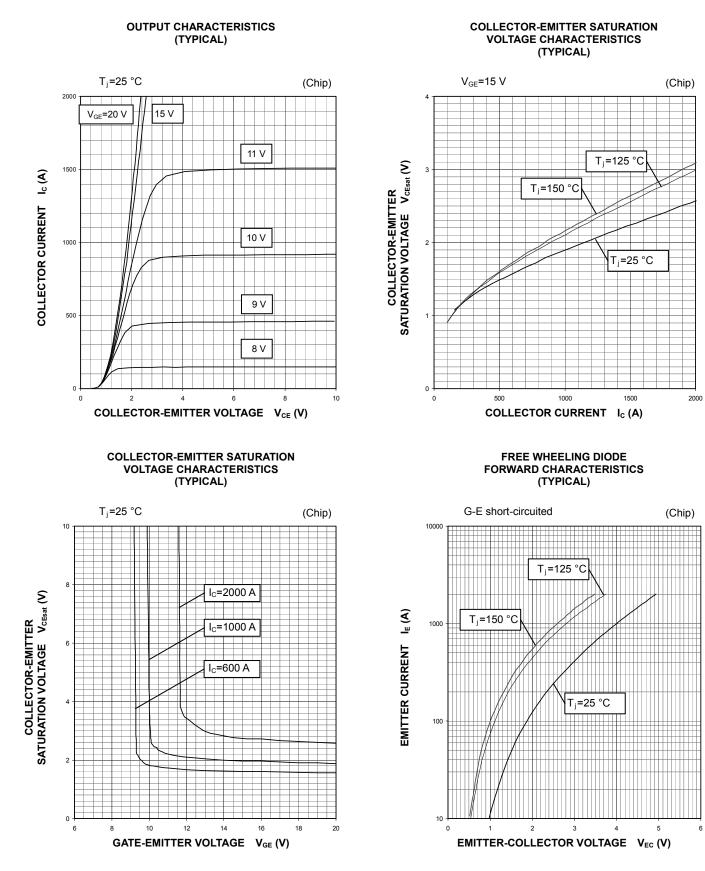
FWDi Reverse recovery energy

Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

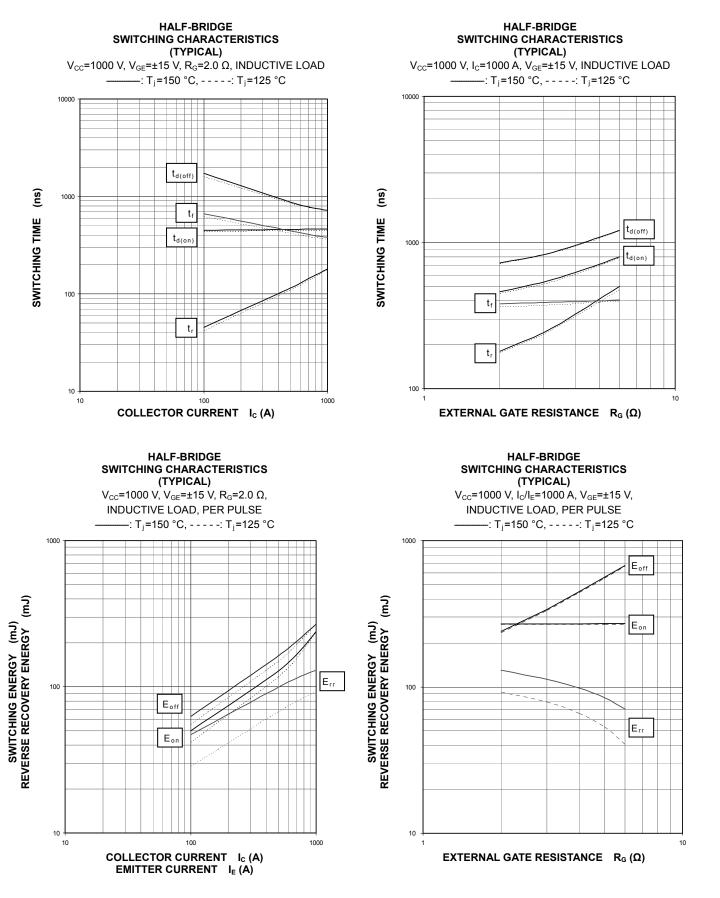
TEST CIRCUIT



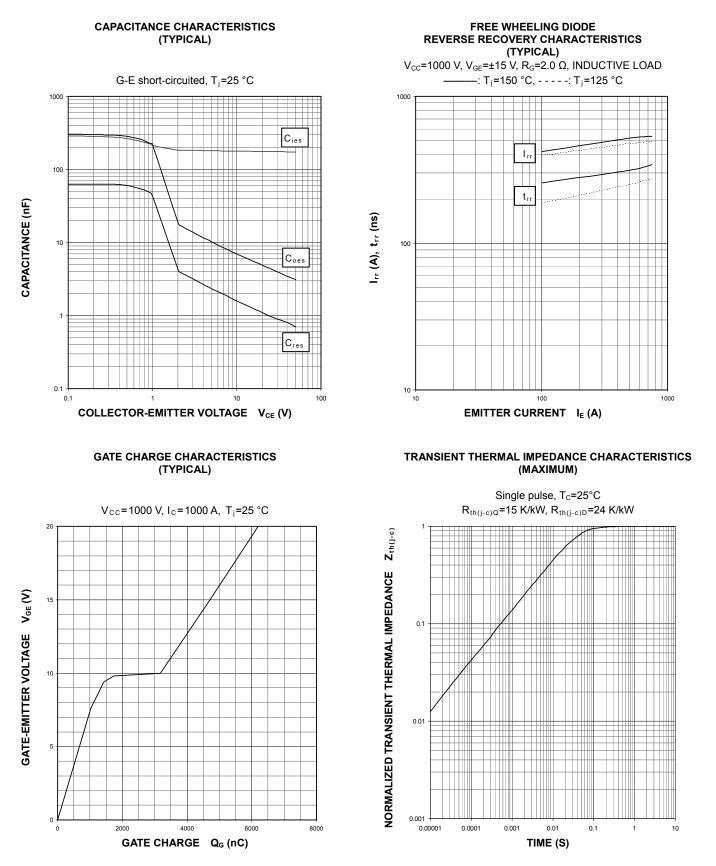
PERFORMANCE CURVES



PERFORMANCE CURVES



PERFORMANCE CURVES



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